

Notice of References Cited

Application/Control No.

10/767,193

Applicant(s)/Patent Under
Reexamination
ODA ET AL.

Examiner

WAE LOUIE

Art Unit

3661

Page 1 of 3

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-4,402,053 A	08-1983	Kelley et al.	700/259
*	B	US-4,412,293 A	10-1983	Kelley et al.	700/259
*	C	US-4,613,269 A	09-1986	Wilder et al.	700/259
*	D	US-4,707,647 A	11-1987	Coldren et al.	382/151
*	E	US-4,731,853 A	03-1988	Hata et al.	382/153
*	F	US-4,753,569 A	06-1988	Pryor, Timothy R.	700/250
*	G	US-4,766,322 A	08-1988	Hashimoto, Hideaki	250/559.33
*	H	US-4,816,733 A	03-1989	Sakakibara et al.	318/568.22
*	I	US-4,831,547 A	05-1989	Ishiguro et al.	700/247
*	J	US-4,975,016 A	12-1990	Pellenc et al.	414/501
*	K	US-4,985,846 A	01-1991	Fallon, Patrick J.	382/153
*	L	US-5,177,563 A	01-1993	Everett et al.	356/621
*	M	US-5,219,264 A	06-1993	McClure et al.	414/730

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	W	
	X	

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.

Notice of References Cited	Application/Control No. 10/767,193		Applicant(s)/Patent Under Reexamination ODA ET AL.	
	Examiner WAE LOUIE		Art Unit 3661	Page 2 of 3

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-5,308,221 A	05-1994	Shimokoshi et al.	414/734
*	B	US-5,321,353 A	06-1994	Furness, Duncan	318/568.11
*	C	US-5,471,541 A	11-1995	Burtnyk et al.	382/153
*	D	US-5,513,299 A	04-1996	Terasaki et al.	700/255
*	E	US-5,608,847 A	03-1997	Pryor, Timothy R.	700/248
*	F	US-5,642,468 A	06-1997	Lee et al.	700/262
*	G	US-5,636,039 A	06-1997	Tanno et al.	358/474
*	H	US-5,740,329 A	04-1998	Lee et al.	700/262
*	I	US-5,751,610 A	05-1998	Gan et al.	700/85
*	J	US-5,825,980 A	10-1998	Danmoto et al.	700/245
*	K	US-5,838,882 A	11-1998	Gan et al.	700/259
*	L	US-5,944,476 A	08-1999	Bacchi et al.	414/783
*	M	US-6,597,971 B2	07-2003	Kanno, Ichiro	700/245

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)				
	U					
	V					
	W					
	X					

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.

Notice of References Cited

Application/Control No.

10/767,193

Applicant(s)/Patent Under
Reexamination
ODA ET AL.

Examiner

WAE LOUIE

Art Unit

3661

Page 3 of 3

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-2004/0186624 A1	09-2004	Oda et al.	700/245
*	B	US-7,244,093 B2	07-2007	Watanabe et al.	414/806
*	C	US-7,313,464 B1	12-2007	Perreault et al.	700/245
	D	US-			
	E	US-			
	F	US-			
	G	US-			
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	W	
	X	

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.